

Accelerating Test, Validation And Debug Of High Speed Serial Interfaces

[DOWNLOAD HERE](#)

1;Acknowledgments;6 2;Table of Contents;8 3;1 Introduction;12 3.1;1.1 Motivation;12 3.2;1.2 Contributions;19 3.3;1.3 Overview of the Book;20 4;2 Background;22 4.1;2.1 High-Speed Serial Communication;22 4.2;2.2 Timing Jitter;32 4.3;2.3 Amplitude Noise;39 5;3 Accelerating Receiver Jitter Tolerance Testing on ATE;47 5.1;3.1 Introduction;48 5.2;3.2 Jitter Test Signal Generation;61 5.3;3.3 Receiver Bit Error Monitoring;75 5.4;3.4 Jitter Tolerance Extrapolation;78 5.5;3.5 Other Applications of the New Method;92 6;4 Transmitter Jitter Extractions on ATE;96 6.1;4.1 Introduction;96 6.2;4.2. Test Setup for Data Acquisition;99 6.3;4.3. Jitter Extraction;106 6.4;4.4 Experimental Results;121 6.5;4.5 Summary;127 7;5 Testing HSSIs with or without ATE Instruments;129 7.1;5.1 DFT in HSSIs;130 7.2;5.2 FPGA-based Bit Error Detection;133 7.3;5.3 Loopback Testing with Jitter Injection;138 7.4;5.4 A Versatile HSSI Testing Scheme;145 8;6 BER Testing Under Noise;156 8.1;6.1 AWG. Generation Overview;156 8.2;6.2 Our Implementation;162 8.3;6.3 Baseband Transmission Testing;176 8.4;6.4 Advantages of Our AWGN Generator;183 9;7 Conclusions;186 10;Reference;189 11;Index;199 EAN/ISBN : 9789048193981
Publisher(s): Springer Netherlands, Springer Science & Business Media Format: ePub/PDF Author(s): Fan, Yongquan - Zilic, Zeljko

[DOWNLOAD HERE](#)

Similar manuals: